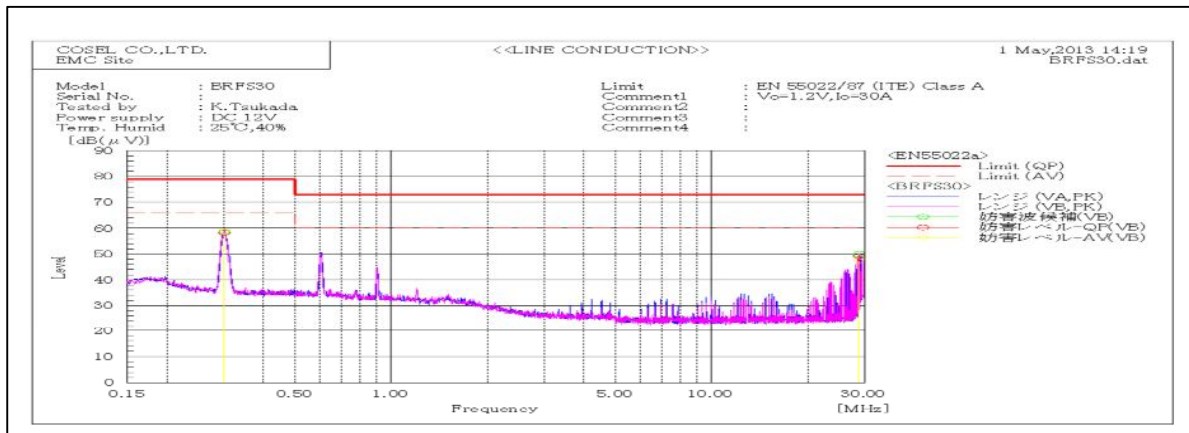
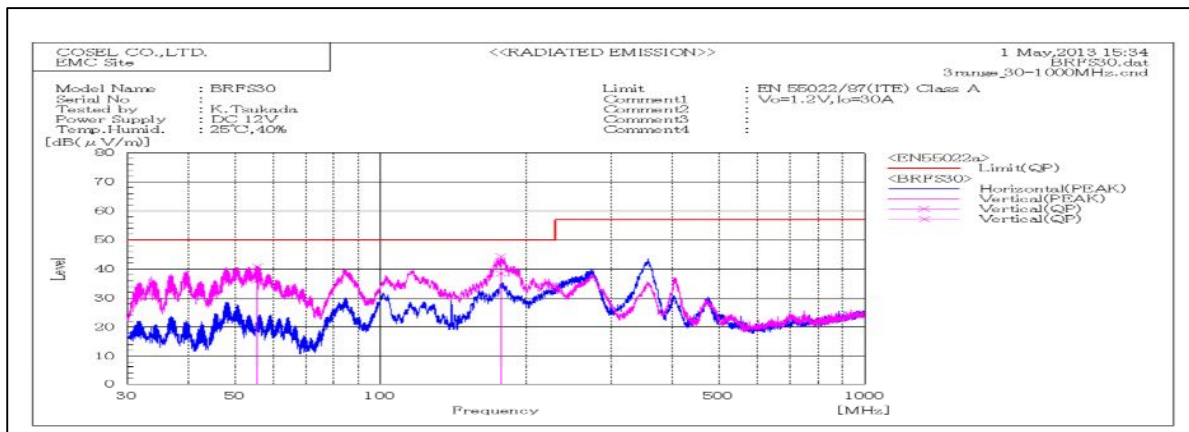


DATA SHEET		Date	16-May-13
Model	BRFS30	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	K.Tsukada



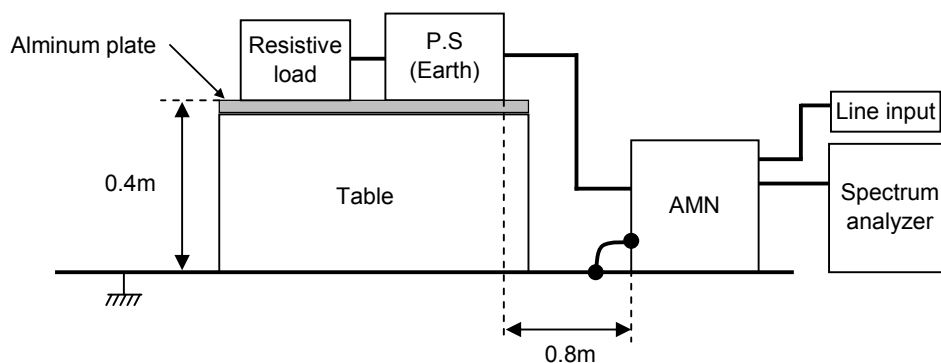
Frequency MHz	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail
		QP	AV		QP	AV	QP	AV	QP	AV	
0.30072	VB	38.3	38.6	20	58.3	58.6	79	66	20.7	7.4	Pass
28.9341	VB	28.3	26.4	20.9	49.2	47.3	73	60	23.8	12.7	Pass



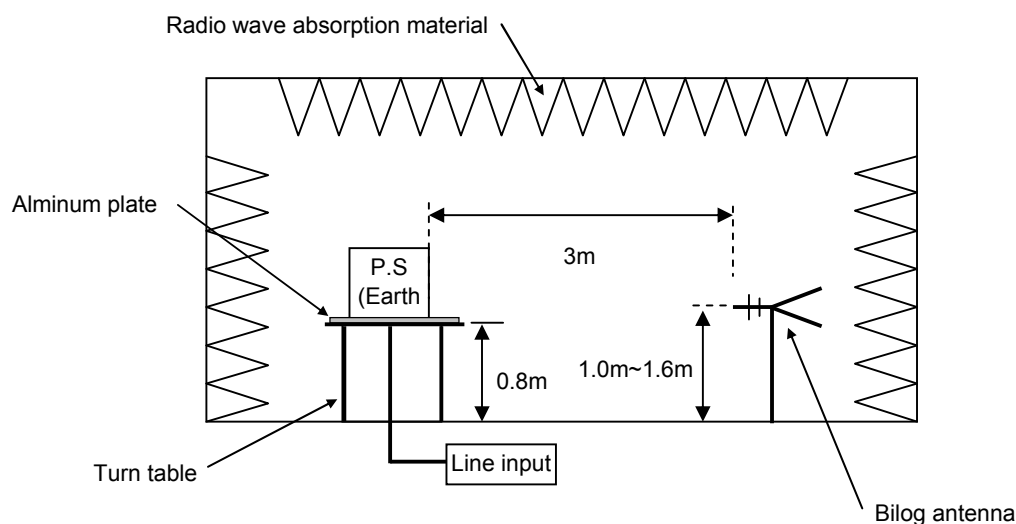
Frequency MHz	Polarization	Stability	Reading dB(μV)	Space Loss dB	Level dB(mW)	Limit dB(mW)	Margin dB	Pass/ Fail	Height cm	Angle deg
			QP		QP	QP	QP			
55.469	V	Stable	60.1	-24.1	36	50	14	Pass	111	54
177.296	V	Stable	54.4	-16	38.4	50	11.6	Pass	116	64

DATA SHEET		Date	16-May-13
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	K.Tsukada

1. Line conduction



2. Radiated emission

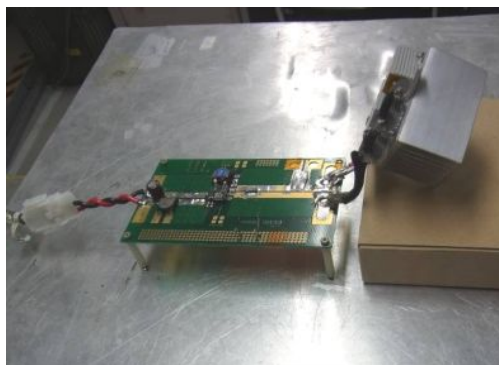


Conditions

Test : EMI
Model Name : BRFS30

○Photographs of Test Set-Up

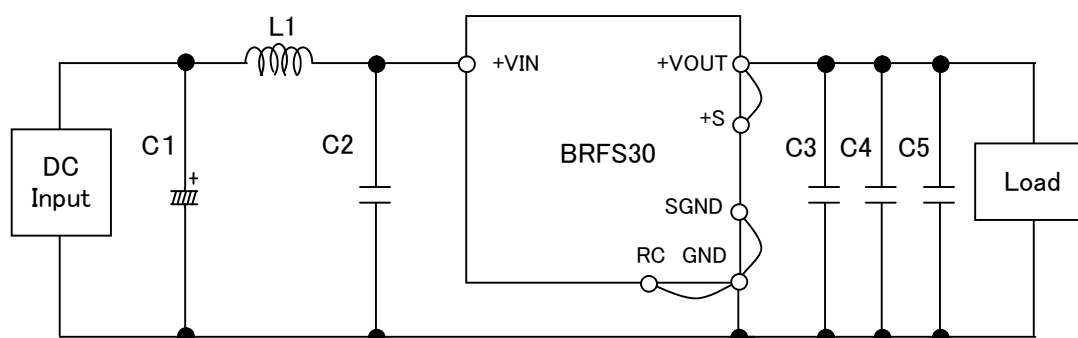
LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry



C1	: 25V	220 μ F	Electrolytic capacitor
C2	: 16V	22 μ F \times 8	Ceramic capacitor
C3, C4, C5	: 6.3V	100 μ F	Ceramic capacitor
L1	: 0.3 μ H	ETQP2H0R3BFA	(Panasonic Electronics Devices)